

2026 Taiwan ESD and Reliability Conference

Dates: Nov. 4-6, 2026

Location: National Yang Ming Chiao Tung University, Hsinchu, Taiwan

Organizer: Taiwan ESD Association (T-ESDA)

Co-organizer: National Yang Ming Chiao Tung University
and Taiwan Reliability Technology Association (TRTA)

Conference Website: <https://alab.iee.nycu.edu.tw/~esd/TESDC/>



ORGANIZING COMMITTEE

Conference Advisor

Ming-Dou Ker, *National Yang Ming Chiao Tung University*

General Chair

Shao-Chang Huang, *Solomon Systech Limited*

TPC Chair

Cher Ming Tan, *Chang Gung University*

Technical Program Committee

(Invitations in Progress)

Organizer

Taiwan ESD Association

President – Chun-Yu Lin

Secretary General – Dunken Lee

Executive Secretary – Lyn Liu

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Call for Papers

Enhancing the research and development capabilities in ESD protection and Reliability technologies has become a critical focus within the electronics industry. The Taiwan ESD Association (T-ESDA) is dedicated to promoting technical exchange in these fields and cordially invites professionals from academia, industry, and research institutions to contribute papers and share practical experiences and research findings related to ESD and Reliability.

The annual symposium not only showcases cutting-edge research from the experts but also serves as a platform for in-depth technical discussions, allowing participants to explore effective solutions to real-world challenges. Through this event, T-ESDA aims to strengthen collaboration among academia, industry, and research communities, and to advance the development of ESD protection and Reliability technologies in response to the evolving needs of the electronics sector.

This conference focuses on the ESD protection and reliability related technologies. Papers related to the studies on analysis and solutions for practical cases are specifically interested. **Topics of interest include, but are not limited to:**

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| ※ Component Level ESD Issue | ※ System Reliability Analysis and Lifetime Prediction |
| ※ System-Level ESD/EMI Issue | ※ Component Reliability Analysis and Lifetime Prediction |
| ※ Factory-Level ESD Issue | ※ Accelerated Stress Testing and Lifetime Extrapolation |
| ※ EDA Verification | ※ Reliability Failure Physics and Failure Mechanisms |
| ※ ESD Materials Technology | ※ Failure Analysis Methodologies |
| ※ ESD Testing – Components, System, Factory & Materials | ※ Maintainability |
| ※ Failure Analysis | ※ Reliability Requirements Setting and Planning |
| ※ Recent Patents on ESD and Reliability | ※ Reliability Screening |

Information for Authors

1. Papers should be accomplished in A4 paper size. It should be in a camera-ready format. The submission shall be made electronically (in PDF format).
2. Paper Submission Deadline: Aug. 15, 2026
3. Paper Acceptance Announcement: Sep. 30, 2026
4. About the paper format and the most updated news release, please visit <https://alab.iee.nycu.edu.tw/~esd/TESDC/>